ELSEVIER

Nuclear Instruments and Methods in Physics Research B 134 (1998) 441–447

NIM B
Beam Interactions with Materials & Atoms

Author index

Al Moussalami, S., see Rouvellou, B. . . . 134 (1998) 287
Alexandrov, Y.M., S.B. Dabagov, M.A. Kumakhov, V.A. Murashova, D.A. Fedin, R.V. Fedorchuk and M.N. Yakimenko, Peculiarities of photon transmission through capillary systems . . . 134 (1998) 174
Allier, C.P., see van't Spijker, J.C. . . . 134 (1998) 304
Alquier, D., see Boussaid, F. . . . 134 (1998) 195
Amaral, L., see Sias, U.S. . . . 134 (1998) 35
Andreyev, A., see Van Duppen, P. . . . 134 (1998) 267
Aoki, Y., see Taguchi, M. . . . 134 (1998) 427
Aoki, Y., see Yamamoto, S. . . . 134 (1998) 400
Augusthy, A., see Kennedy, V.J. . . . 134 (1998) 165
Augusthy, A., see Kennedy, V.J. . . . 134 (1998) 224
Äystö, J., see Van Duppen, P. . . . 134 (1998) 267

Barnes, P., A.C. Jupe, S.L. Colston, S.D. Jacques, A. Grant, T. Rathbone, M. Miller, S.M. Clark and R.J. Cernik, A new three-angle energy-dispersive diffractometer (*Letter to the Editor*) . . . 134 (1998) 310
Battke, M., see Rogalla, M. . . . 134 (1998) 53
Baudin, K., E.S. Parilis, J.F. Blankenship, M.J. Van Stipdonk and E.A. Schweikert, Sublinear effect in light emission from cesium iodide bombarded by keV polyatomic projectiles . . . 134 (1998) 352
Behar, M., see Sias, U.S. . . . 134 (1998) 35
Bell, E.W., see Parks, D.C. . . . 134 (1998) 46
Belymam, A., A. Hoummada, J. Collot, P. de Saintignon, G. Mahout and B. Merkel, Measurements of the neutron yield and the neutron energy distribution from the $^{9}Be(d,n)^{10}$ B reaction on a thick be target at an incident deuteron energy of 20.2 MeV. . . . 134 (1998) 217
Benz, K.W., see Rogalla, M. . . . 134 (1998) 53
Benzohra, M., see Boussaid, F. . . . 134 (1998) 195
Bera, S., see Das, A. . . . 134 (1998) 377
Berger, M.J.A method for determining the 2π-counting efficiency of beta-particle sources . . . 134 (1998) 276
Berland, N., see Rouvellou, B. . . . 134 (1998) 287
Bichsel, H. and M. Inokuti, Difference in stopping power for protons and deuterons of a given speed . . . 134 (1998) 161
Bielajew, A.F., see Kawrakow, I. . . . 134 (1998) 325
Bizau, J.-M., see Rouvellou, B. . . . 134 (1998) 287
Blancard, C., see Rouvellou, B. . . . 134 (1998) 287
Blankenship, J.F., see Baudin, K. . . . 134 (1998) 352
Blässer, S., see Moons, R. . . . 134 (1998) 181
Bouisset, E., see Rouvellou, B. . . . 134 (1998) 287
Boulais, K.A., see Stumborg, M.F. . . . 134 (1998) 77
Boussaid, F., M. Benzohra, F. Olivie, D. Alquier and A. Martinez, Electrically active defects in BF_2^+ implanted and germanium preamorphized silicon . . . 134 (1998) 195
Brandan, M.E., see Gamboa-deBuen, I. . . . 134 (1998) 136
Breese, M.B.H. and D.G. de Kerckhove, Transmission ion microscopy using a quadrupole triplet as an objective lens (*Letter to the Editor*) . . . 134 (1998) 431
Bremer, J.-H., see Metzner, H. . . . 134 (1998) 249
Brenn, R., see Ermer, H. . . . 134 (1998) 237
Brodeur, C., see Narayan, C. . . . 134 (1998) 271
Busch, H., see Ernst, R. . . . 134 (1998) 262
Buslaps, T., see Fajardo, P. . . . 134 (1998) 337

0168-583X/98/$19.00 © 1998 Elsevier Science B.V. All rights reserved

Cao, D.-X., see Xie, D.-Z. . . . 134 (1998) 22
Cernik, R.J., see Barnes, P. . . . 134 (1998) 310
Cervena, J., see Fink, D. . . . 134 (1998) 61
Chadderton, L.T., see Fink, D. . . . 134 (1998) 87
Chu, T.K., see Stumborg, M.F. . . . 134 (1998) 77
Chu, W.K., see Li, Y. . . . 134 (1998) 107
Clark, S.M., see Barnes, P. . . . 134 (1998) 310
Climent-Font, A., G. Demortier, C. Palacio, I. Montero, J.L. Ruvalcaba-Sil and D. Díaz, Characterisation of archaeological bronzes using PIXE, PIGE, RBS and AES spectrometries . . . 134 (1998) 229
Collot, J., see Belymam, A. . . . 134 (1998) 217
Colston, S.L., see Barnes, P. . . . 134 (1998) 310
Conrad, J., see Metzner, H. . . . 134 (1998) 249
Croitoru, N., G. David, P.G. Rancoita, M. Rattaggi and A. Seidman, Frequency dependence of ac conductance of neutron irradiated silicon detectors to fluences up to 10^{16} n/cm^2 . . . 134 (1998) 209
Cubaynes, D., see Rouvellou, B. . . . 134 (1998) 287
Cui, X.T., see Li, Y. . . . 134 (1998) 107

Dabagov, S.B., see Alexandrov, Y.M. . . . 134 (1998) 174
Das, A., S. Bera, S. Dhara and A. Patnaik, Physical and chemical implications of 100 keV H^+ implantation of laser ablated PPS thin films . . . 134 (1998) 377
David, G., see Croitoru, N. . . . 134 (1998) 209
de Kerckhove, D.G., see Breese, M.B.H. . . . 134 (1998) 431
de Saintignon, P., see Belymam, A. . . . 134 (1998) 217
De Wachter, J., see Moons, R. . . . 134 (1998) 181
Dekoster, J., see Moons, R. . . . 134 (1998) 181
Demortier, G., see Climent-Font, A. . . . 134 (1998) 229
Deshmukh, B.T., see Deshpande, S.P. . . . 134 (1998) 385
Deshpande, S.P., S.J. Dhoble, W.K. Pokale, B.T. Deshmukh, R.B. Pode and T.K. Gundurao, Radiation effect on the luminescence of $LiYF_4:Er^{3+}$ . . . 134 (1998) 385
Dhal, B.B., see Kennedy, V.J. . . . 134 (1998) 165
Dhara, S., see Das, A. . . . 134 (1998) 377
Dhoble, S.J., see Deshpande, S.P. . . . 134 (1998) 385
Díaz, D., see Climent-Font, A. . . . 134 (1998) 229
Diehl, S., see Rouvellou, B. . . . 134 (1998) 287
Dorenbos, P., see van't Spijker, J.C. . . . 134 (1998) 304
Duda, N., see Rogalla, M. . . . 134 (1998) 53

Eftekhari, A., see Singh, J.J. . . . 134 (1998) 113
Ermer, H., O. Pfaff, W. Straub, M. Geoghegan and R. Brenn, Deuterium depth profiling in polymers using heavy ion elastic recoil detection . . . 134 (1998) 237
Ernst, R., K.-H. Speidel, A. Gohla, L. Kleinen, H. Busch, U. Grabowy, V. Roth, B. Heller, G. Jakob and J. Gerber, Transient magnetic fields and electron polarizations of H-like oxygen ions in crystalline iron and amorphous iron–boron compounds . . . 134 (1998) 262
Ettema, A.R.H.F., see van't Spijker, J.C. . . . 134 (1998) 304
Evensen, A.-H., see Van Duppen, P. . . . 134 (1998) 267

Fajardo, P., V. Honkimäki, T. Buslaps and P. Suortti, Experimental validation of multiple scattering calculations with high energy X-ray photons . . . 134 (1998) 337
Fedin, D.A., see Alexandrov, Y.M. . . . 134 (1998) 174
Fedorchuk, R.V., see Alexandrov, Y.M. . . . 134 (1998) 174
Fink, D., J. Vacik, J. Cervena, V. Hnatowicz, Y. Kobayashi, S. Hishita, S. Ghosh and R. Klett, On the uptake of aqueous tracer solutions by pristine and ion-irradiated PEEK . . . 134 (1998) 61
Fink, D., M. Müller, P. Szimkoviak, R. Klett, J. Vacik, V. Hnatowicz and L.T. Chadderton, Rutherford backscattering of laterally heterogeneous structures: The determination of radial density distributions in ion tracks in collodium . . . 134 (1998) 87
Fink, D., see Sias, U.S. . . . 134 (1998) 35
Fujioka, M., see Muramatsu, H. . . . 134 (1998) 126

Furuyama, Y., see Kitamura, A. 134 (1998) 98
Fyodorov, A.A., W.P. Trower and R.F. Zuevsky, A broad range YAP–plastic phoswich dosimeter 134 (1998) 413

Gamboa-deBuen, I., C. Ruiz, A. Oliver, K. López and M.E. Brandan, Measurement of the thermoluminescent response (supralinearity and efficiency) of LiF : Mg,Ti exposed to 0.7 MeV protons 134 (1998) 136
Gao, J., see Zhang, M. 134 (1998) 360
Gao, Q., see Wei, Z. 134 (1998) 191
Geoghegan, M., see Ermer, H. 134 (1998) 237
Geppert, R., see Rogalla, M. 134 (1998) 53
Gerber, J., see Ernst, R. 134 (1998) 262
Ghosh, S., see Fink, D. 134 (1998) 61
Gillaspy, J.D., see Parks, D.C. 134 (1998) 46
Gohla, A., see Ernst, R. 134 (1998) 262
Göppert, R., see Rogalla, M. 134 (1998) 53
Gösele, U., see Zhang, M. 134 (1998) 360
Gossla, M., see Metzner, H. 134 (1998) 249
Grabowy, U., see Ernst, R. 134 (1998) 262
Grant, A., see Barnes, P. 134 (1998) 310
Greenwood, C.L., see Rees, J.A. 134 (1998) 73
Grigorjeva, V., see Grishmanov, V. 134 (1998) 27
Grishmanov, V., S. Tanaka, J. Tiliks, G. Kizane, A. Supe and V. Grigorjeva, The role of radiolysis products in in situ luminescence of Li_2O 134 (1998) 27
Grötzschel, R., see Wieser, E. 134 (1998) 365
Gundurao, T.K., see Deshpande, S.P. 134 (1998) 385
Gutjahr, K., see Zhang, M. 134 (1998) 360

Hahn, Th., see Metzner, H. 134 (1998) 249
Hamanaka, H., see Maeda, K. 134 (1998) 418
Han, G., see Wei, Z. 134 (1998) 191
Hasegawa, K., see Maeda, K. 134 (1998) 418
Hawes, C.D., see Pierson, K.W. 134 (1998) 13
Heller, B., see Ernst, R. 134 (1998) 262
Hemment, P.L.F., see Zhang, M. 134 (1998) 360
Hiratsuka, H., see Taguchi, M. 134 (1998) 427
Hishita, S., see Fink, D. 134 (1998) 61
Hnatowicz, V., see Fink, D. 134 (1998) 61
Hnatowicz, V., see Fink, D. 134 (1998) 87
Honkimäki, V., see Fajardo, P. 134 (1998) 337
Hoogduin, J.M. and J. van Klinken, Consideration of $R_2Fe_{14}B$ layers as targets with polarized electrons (*Letter to the Editor*) 134 (1998) 149
Hoummada, J., see Belymam, A. 134 (1998) 217
Huang, W., Z. Yu and Y. Zhang, Repair by radiation itself or not? A study of threonine irradiated by keV ion 134 (1998) 202
Huber, G., see van't Spijker, J.C. 134 (1998) 304
Huhta, M., see Van Duppen, P. 134 (1998) 267
Huyse, M., see Van Duppen, P. 134 (1998) 267

Inokuti, M., see Bichsel, H. 134 (1998) 161
Irsigler, R., see Rogalla, M. 134 (1998) 53
Ishii, H., see Muramatsu, H. 134 (1998) 126
ISOLDE collaboration, see Van Duppen, P. 134 (1998) 267
Iyer, R.H., see Pandey, A.K. 134 (1998) 393

Jacques, S.D., see Barnes, P. 134 (1998) 310
Jakob, G., see Ernst, R. 134 (1998) 262
Janžekovič, H., Measurements of ionization cross sections of Ti and Cu induced by low energy Li and B ion impact 134 (1998) 319
Joerger, W., see Rogalla, M. 134 (1998) 53

Jokinen, A., see Van Duppen, P. . . . 134 (1998) 267
Journel, L., see Rouvellou, B. . . . 134 (1998) 287
Jupe, A.C., see Barnes, P. . . . 134 (1998) 310
Kalsi, P.C., see Pandey, A.K. . . . 134 (1998) 393
Karny, M., see Van Duppen, P. . . . 134 (1998) 267
Kaschny, J.R., see Sias, U.S. . . . 134 (1998) 35
Kawrakow, I. and A.F. Bielajew, On the representation of electron multiple elastic-scattering distributions for Monte Carlo calculations . . . 134 (1998) 325
Kegel, G.H.R., see Narayan, C. . . . 134 (1998) 271
Kennedy, V.J., A. Augusthy, K.M. Varier, P. Magudapathy, K.G.M. Nair, B.B. Dhal and H.C. Padhi, L X-ray production cross sections and their ratios in Ta, W and Pt for proton impact in the energy range 2–5.2 MeV . . . 134 (1998) 165
Kennedy, V.J., A. Augusthy, K.M. Varier, P. Magudapathy, S. Panchapakesan, C. Ramesh, K.G.M. Nair and V. Vijayan, PIXE analysis of trace pollutants in Chaliyar river water in Malabar, India . . . 134 (1998) 224
Kitamura, A., T. Tamai, A. Taniike, Y. Furuyama, T. Maeda, N. Ogiwara and M. Saidoh, Simulation of ERD spectra for a surface with a periodic roughness . . . 134 (1998) 98
Kizane, G., see Grishmanov, V. . . . 134 (1998) 27
Kleinen, L., see Ernst, R. . . . 134 (1998) 262
Klett, R., see Fink, D. . . . 134 (1998) 61
Klett, R., see Fink, D. . . . 134 (1998) 87
Kobayashi, Y., see Fink, D. . . . 134 (1998) 61
Koizumi, M., see Muramatsu, H. . . . 134 (1998) 126
Krueger, T.D., see Pierson, K.W. . . . 134 (1998) 13
Kudo, H., see Yamamoto, S. . . . 134 (1998) 400
Kugler, E., see Van Duppen, P. . . . 134 (1998) 267
Kumakhov, M.A., see Alexandrov, Y.M. . . . 134 (1998) 174
Kurpeta, J., see Van Duppen, P. . . . 134 (1998) 267

Langouche, G., see Moons, R. . . . 134 (1998) 181
Lazurik, V. and V. Moskvin, A study of primary electron charge deposition near the surface of a target by Monte Carlo simulation . . . 134 (1998) 1
Lettry, J., see Van Duppen, P. . . . 134 (1998) 267
Li, Y., J.R. Liu, X.T. Cui and W.K. Chu, RBS and ion channeling studies of Ag-doped $YBa_2Cu_3O_{7-\delta}$ targets and films . . . 134 (1998) 107
Li, Q., see Wei, Z. . . . 134 (1998) 191
Liang, J.H., Theoretical formulation for calculating lateral spread of implanted ions . . . 134 (1998) 157
Lin, C., see Zhang, M. . . . 134 (1998) 360
Liu, J.R., see Li, Y. . . . 134 (1998) 107
López, K., see Gamboa-deBuen, I. . . . 134 (1998) 136
Ludwig, J., see Rogalla, M. . . . 134 (1998) 53

Maeda, K., K. Hasegawa, H. Hamanaka and K. Ogiwara, Development of an in-air high-resolution PIXE system . . . 134 (1998) 418
Maeda, T., see Kitamura, A. . . . 134 (1998) 98
Magudapathy, P., see Kennedy, V.J. . . . 134 (1998) 165
Magudapathy, P., see Kennedy, V.J. . . . 134 (1998) 224
Mahout, G., see Belymam, A. . . . 134 (1998) 217
Martinez, A., see Boussaid, F. . . . 134 (1998) 195
Matsumoto, Y., see Taguchi, M. . . . 134 (1998) 427
Matsunami, N., Sputtering yields of $YBa_2Cu_3O_7$ and $Bi_2Sr_2Ca_2Cu_3O_{10}$ by 100 keV Ar^+ impact at normal incidence . . . 134 (1998) 346
Merkel, B., see Belymam, A. . . . 134 (1998) 217
Metzner, H., Th. Hahn, M. Gossla, J. Conrad and J.-H. Bremer, Rutherford backscattering spectroscopy of rough films: Experimental aspects . . . 134 (1998) 249
Miller, M., see Barnes, P. . . . 134 (1998) 310
Mittler, A., see Narayan, C. . . . 134 (1998) 271
Miura, T., see Muramatsu, H. . . . 134 (1998) 126

Montero, I., see Climent-Font, A. 134 (1998) 229
Moons, R., S. Blässer, J. Dekoster, A. Vantomme, J. De Wachter and G. Langouche, ⟨1 0 0⟩ Axial ion channeling in Fe single crystals: Flux related phenomena in the near surface region 134 (1998) 181
Moskvin, V., see Lazurik, V. 134 (1998) 1
Mücklich, A., see Wieser, E. 134 (1998) 365
Müller, M., see Fink, D. 134 (1998) 87
Muramatsu, H., H. Ishii, E. Tanaka, A. Osa, M. Koizumi, T. Sekine, T. Miura and M. Fujioka, A simple retardation system for low-energy implantation of mass-separated radioactive ions 134 (1998) 126
Murashova, V.A., see Alexandrov, Y.M. 134 (1998) 174

Nair, K.G.M., see Kennedy, V.J. 134 (1998) 165
Nair, K.G.M., see Kennedy, V.J. 134 (1998) 224
Namba, H., see Taguchi, M. 134 (1998) 427
Naramoto, H., see Yamamoto, S. 134 (1998) 400
Narayan, C., M. O'Connor, G.H.R. Kegel, A. Mittler and C. Brodeur, Analysis of Van de Graaff ion source with Rutherford backscattering spectroscopy 134 (1998) 271
Narumi, K., see Yamamoto, S. 134 (1998) 400
Nieminen, A., see Van Duppen, P. 134 (1998) 267

O'Connor, M., see Narayan, C. 134 (1998) 271
Obert, J., see Rouvellou, B. 134 (1998) 287
Ogiwara, K., see Maeda, K. 134 (1998) 418
Ogiwara, N., see Kitamura, A. 134 (1998) 98
Oliver, A., see Gamboa-deBuen, I. 134 (1998) 136
Olivie, F., see Boussaid, F. 134 (1998) 195
Osa, A., see Muramatsu, H. 134 (1998) 126

Padhi, H.C., see Kennedy, V.J. 134 (1998) 165
Palacio, C., see Climent-Font, A. 134 (1998) 229
Pan, H.-C., see Xie, D.-Z. 134 (1998) 22
Panchapakesan, S., see Kennedy, V.J. 134 (1998) 224
Pandey, A.K., P.C. Kalsi and R.H. Iyer, Effects of high intensity ultrasound in chemical etching of particle tracks in solid state nuclear track detectors 134 (1998) 393
Parilis, E.S., see Baudin, K. 134 (1998) 352
Parks, D.C., M.P. Stöckli, E.W. Bell, L.P. Ratliff, R.W. Schmieder, F.G. Serpa and J.D. Gillaspy, Non-kinetic damage on insulating materials by highly charged ion bombardment 134 (1998) 46
Pater, R.H., see Singh, J.J. 134 (1998) 113
Patnaik, A., see Das, A. 134 (1998) 377
Pfaff, O., see Ermer, H. 134 (1998) 237
Pierson, K.W., C.D. Hawes and T.D. Krueger, Temperature dependence of the total sputtering yield of a two-phase Ag/Cu (65/35 at%) alloy for 200 eV Ar^+ ions 134 (1998) 13
Plochocki, A., see Van Duppen, P. 134 (1998) 267
Pode, R.B., see Deshpande, S.P. 134 (1998) 385
Pokale, W.K., see Deshpande, S.P. 134 (1998) 385
Price, J.L., see Stumborg, M.F. 134 (1998) 77
Prokert, F., see Wieser, E. 134 (1998) 365
Putaux, J.-C., see Rouvellou, B. 134 (1998) 287

Ramdhane, M., see Van Duppen, P. 134 (1998) 267
Ramesh, C., see Kennedy, V.J. 134 (1998) 224
Rancoita, P.G., see Croitoru, N. 134 (1998) 209
Rathbone, T., see Barnes, P. 134 (1998) 310
Ratliff, L.P., see Parks, D.C. 134 (1998) 46
Rattaggi, M., see Croitoru, N. 134 (1998) 209
Ravn, H.L., see Van Duppen, P. 134 (1998) 267
Rees, J.A., D.L. Seymour, C.L. Greenwood and A. Scott, An improved method for the study of neutral species produced in processing plasmas 134 (1998) 73

Rogalla, M., M. Battke, N. Duda, R. Geppert, R. Göppert, R. Irsigler, J. Ludwig, K. Runge, Th. Schmid, W. Joerger and K.W. Benz, Determination of the EL2 introduction rate and Fermi-level shift due to proton and pion irradiation in semi-insulating GaAs 134 (1998) 53
Roth, V., see Ernst, R. 134 (1998) 262
Rouvellou, B., J.-M. Bizau, J. Obert, S. Al Moussalami, N. Berland, C. Blancard, E. Bouisset, D. Cubaynes, S. Diehl, L. Journel, J.-C. Putaux, C. Vinsot and F.J. Wuilleumier, Photoelectron spectroscopy experiments on singly charged positive-ions using synchrotron radiation 134 (1998) 287
Ruiz, C., see Gamboa-deBuen, I. 134 (1998) 136
Runge, K., see Rogalla, M. 134 (1998) 53
Ruvalcaba-Sil, J.L., see Climent-Font, A. 134 (1998) 229
Rykaczewski, K., see Van Duppen, P. 134 (1998) 267

Saidoh, M., see Kitamura, A. 134 (1998) 98
Sánchez, G., see Sias, U.S. 134 (1998) 35
Santiago, F., see Stumborg, M.F. 134 (1998) 77
Schmid, Th., see Rogalla, M. 134 (1998) 53
Schmieder, R.W., see Parks, D.C. 134 (1998) 46
Schweikert, E.A., see Baudin, K. 134 (1998) 352
Scott, A., see Rees, J.A. 134 (1998) 73
Seidman, A., see Croitoru, N. 134 (1998) 209
Sekine, T., see Muramatsu, H. 134 (1998) 126
Serpa, F.G., see Parks, D.C. 134 (1998) 46
Seymour, D.L., see Rees, J.A. 134 (1998) 73
Sias, U.S., G. Sánchez, J.R. Kaschny, L. Amaral, M. Behar and D. Fink, Polymer thermal protection induced by ion beam irradiation 134 (1998) 35
Sigmund, P., Erratum to: "Statistical theory of charged-particle stopping and straggling in the presence of charge exchange" [Nucl. Instr. and Meth. B 69 (1992) 113] 134 (1998) 435
Singh, J.J., R.H. Pater and A. Eftekhari, Microstructural characterization of semi-interpenetrating polymer networks by positron lifetime spectroscopy 134 (1998) 113
Speidel, K.-H., see Ernst, R. 134 (1998) 262
Stöckli, M.P., see Parks, D.C. 134 (1998) 46
Straub, W., see Ermer, H. 134 (1998) 237
Stumborg, M.F., F. Santiago, T.K. Chu, K.A. Boulais and J.L. Price, Heavy ion backscattering spectroscopy (HIBS) analysis of gallium arsenide diffusion into barium fluoride layers grown by molecular beam epitaxy 134 (1998) 77
Suortti, P., see Fajardo, P. 134 (1998) 337
Supe, A., see Grishmanov, V. 134 (1998) 27
Szerypo, J., see Van Duppen, P. 134 (1998) 267
Szimkoviak, P., see Fink, D. 134 (1998) 87
Szymański, K., Magnetic texture determination by means of the monochromatic circularly polarized Mössbauer spectroscopy 134 (1998) 405

Taguchi, M., Y. Matsumoto, H. Namba, Y. Aoki and H. Hiratsuka, Chemical tracks of heavy ions for 1,2,4,5-tetracyanobenzene anion radical formation (*Letter to the Editor*) 134 (1998) 427
Tamai, T., see Kitamura, A. 134 (1998) 98
Tanaka, E., see Muramatsu, H. 134 (1998) 126
Tanaka, S., see Grishmanov, V. 134 (1998) 27
Taniike, A., see Kitamura, A. 134 (1998) 98
Tiliks, J., see Grishmanov, V. 134 (1998) 27
Trower, W.P., see Fyodorov, A.A. 134 (1998) 413
Tsuchiya, B., see Yamamoto, S. 134 (1998) 400

Vacik, J., see Fink, D. 134 (1998) 61
Vacik, J., see Fink, D. 134 (1998) 87
Van Duppen, P., A. Andreyev, J. Äystö, A.-H. Evensen, M. Huhta, M. Huyse, A. Jokinen, M. Karny, E. Kugler, J. Kurpeta, J. Lettry, A. Nieminen, A. Plochocki, M. Ramdhane, H.L. Ravn, K. Rykaczewski, J. Szerypo, G. Walter, A. Wöhr and ISOLDE collaboration, A new pulsed release method for element selective production of neutron rich isotopes near ^{208}Pb 134 (1998) 267

van Eijk, C.W.E., see van't Spijker, J.C. 134 (1998) 304
van Klinken, J., see Hoogduin, J.M. 134 (1998) 149
Van Stipdonk, M.J., see Baudin, K. 134 (1998) 352
van't Spijker, J.C., P. Dorenbos, C.P. Allier, C.W.E. van Eijk, A.R.H.F. Ettema and G. Huber, $Lu_2S_3:Ce^{3+}$, A new red luminescing scintillator (*Letter to the Editor*) 134 (1998) 304
Vantomme, A., see Moons, R. 134 (1998) 181
Varier, K.M., see Kennedy, V.J. 134 (1998) 165
Varier, K.M., see Kennedy, V.J. 134 (1998) 224
Vijayan, V., see Kennedy, V.J. 134 (1998) 224
Vinsot, C., see Rouvellou, B. 134 (1998) 287

Walter, G., see Van Duppen, P. 134 (1998) 267
Wang, L., see Zhang, M. 134 (1998) 360
Wei, Z., G. Han, G. Zhou, Q. Li, H. Xie and Q. Gao, An important mechanism of crop breeding with ultralow energy ion implantation 134 (1998) 191
Wieser, E., R. Grötzschel, A. Mücklich and F. Prokert, Microstructure and tribological properties of aluminium implanted with high doses of nickel 134 (1998) 365
Wöhr, A., see Van Duppen, P. 134 (1998) 267
Wuilleumier, F.J., see Rouvellou, B. 134 (1998) 287

Xie, D.-Z., D.-Z. Zhu, D.-X. Cao, G.-Q. Yu, H.-C. Pan and T.-A.B.H.J. Xu, Effects of environment on annealing behavior of In^+ implanted c-axis sapphire 134 (1998) 22
Xie, H., see Wei, Z. 134 (1998) 191
Xu, T.-A.B.H.J., see Xie , D.-Z. 134 (1998) 22

Yakimenko, M.N., see Alexandrov, Y.M. 134 (1998) 174
Yamamoto, S., H. Naramoto, K. Narumi, B. Tsuchiya, Y. Aoki and H. Kudo, Characterization of single-crystalline Nb films on sapphire by RBS/channeling technique 134 (1998) 400
Yamazaki, H., Matrix effects in SIMS analysis of high-dose boron implanted silicon wafers 134 (1998) 121
Yu, G.-Q., see Xie , D.-Z. 134 (1998) 22
Yu, Z., see Huang, W. 134 (1998) 202

Zhang, Y., see Huang, W. 134 (1998) 202
Zhang, M., L. Wang, J. Gao, C. Lin, P.L.F. Hemment, K. Gutjahr and U. Gösele, Gettering of Cu by He-induced cavities in SIMOX materials 134 (1998) 360
Zhou, G., see Wei, Z. 134 (1998) 191
Zhu, D.-Z., see Xie , D.-Z. 134 (1998) 22
Zuevsky, R.F., see Fyodorov, A.A. 134 (1998) 413

Nuclear Instruments and Methods in Physics Research B 134 (1998) 449–451

ELSEVIER

NIM B
Beam Interactions with Materials & Atoms

Subject index

Basic Data for Materials Modification and Analysis

Theoretical formulation for calculating lateral spread of implanted ions, J.H. Liang 134 (1998) 157
Difference in stopping power for protons and deuterons of a given speed, H. Bichsel and M. Inokuti 134 (1998) 161
L X-ray production cross sections and their ratios in Ta, W and Pt for proton impact in the energy range 2–5.2 MeV, V.J. Kennedy, A. Augusthy, K.M. Varier, P. Magudapathy, K.G.M. Nair, B.B. Dhal and H.C. Padhi 134 (1998) 165
Measurements of ionization cross sections of Ti and Cu induced by low energy Li and B ion impact, H. Janžekovič 134 (1998) 319
On the representation of electron multiple elastic-scattering distributions for Monte Carlo calculations, I. Kawrakow and A.F. Bielajew 134 (1998) 325
Experimental validation of multiple scattering calculations with high energy X-ray photons, P. Fajardo, V. Honkimäki, T. Buslaps and P. Suortti 134 (1998) 337

Atomic Collisions in Solids

A study of primary electron charge deposition near the surface of a target by Monte Carlo simulation, V. Lazurik and V. Moskvin 134 (1998) 1
Temperature dependence of the total sputtering yield of a two-phase Ag/Cu (65/35 at%) alloy for 200 eV Ar^+ ions, K.W. Pierson, C.D. Hawes and T.D. Krueger 134 (1998) 13
Peculiarities of photon transmission through capillary systems, Yu.M. Alexandrov, S.B. Dabagov, M.A. Kumakhov, V.A. Murashova, D.A. Fedin, R.V. Fedorchuk and M.N. Yakimenko 134 (1998) 174
⟨1 0 0⟩ Axial ion channeling in Fe single crystals: Flux related phenomena in the near surface region, R. Moons, S. Blässer, J. Dekoster, A. Vantomme, J. De Wachter and G. Langouche 134 (1998) 181
Sputtering yields of $YBa_2Cu_3O_7$ and Bi_2Sr_2 $Ca_2Cu_3O_{10}$ by 100 keV Ar^+ impact at normal incidence, N. Matsunami 134 (1998) 346
Sublinear effect in light emission from cesium iodide bombarded by keV polyatomic projectiles, K. Baudin, E.S. Parilis, J.F. Blankenship, M.J. Van Stipdonk and E.A. Schweikert 134 (1998) 352

Ion Beam Modification of Materials

Effects of environment on annealing behavior of In^+ implanted *c*-axis sapphire, D.-Z. Xie, D.-Z. Zhu, D.-X. Cao, G.-Q. Yu, H.-C. Pan and H.-J. Xu 134 (1998) 22
The role of radiolysis products in in situ luminescence of Li_2O, V. Grishmanov, S. Tanaka, J. Tiliks, G. Kizane, A. Supe and V. Grigorjeva 134 (1998) 27
Polymer thermal protection induced by ion beam irradiation, U.S. Sias, G. Sánchez, J.R. Kaschny, L. Amaral, M. Behar and D. Fink 134 (1998) 35
An important mechanism of crop breeding with ultralow energy ion implantation, Z. Wei, G. Han, G. Zhou, Q. Li, H. Xie and Q. Gao 134 (1998) 191
Electrically active defects in BF_2^+ implanted and germanium preamorphized silicon, F. Boussaid, M. Benzohra, F. Olivie, D. Alquier and A. Martinez 134 (1998) 195
Gettering of Cu by He-induced cavities in SIMOX materials, M. Zhang, L. Wang, J. Gao, C. Lin, P.L.F. Hemment, K. Gutjahr and U. Gösele 134 (1998) 360
Microstructure and tribological properties of aluminium implanted with high doses of nickel, E. Wieser, R. Grötzschel, A. Mücklich and F. Prokert 134 (1998) 365

0168-583X/97/$17.00 © 1997 Elsevier Science B.V. All rights reserved

Effects of Radiation

Non-kinetic damage on insulating materials by highly charged ion bombardment, D.C. Parks, M.P. Stöckli, E.W. Bell, L.P. Ratliff, R.W. Schmieder, F.G. Serpa and J.D. Gillaspy 134 (1998) 46
Determination of the EL2 introduction rate and Fermi-level shift due to proton and pion irradiation in semi-insulating GaAs, M. Rogalla, M. Battke, N. Duda, R. Geppert, R. Göppert, R. Irsigler, J. Ludwig, K. Runge, Th. Schmid, W. Joerger and K.W. Benz 134 (1998) 53
On the uptake of aqueous tracer solutions by pristine and ion-irradiated PEEK, D. Fink, J. Vacik, J. Cervena, V. Hnatowicz, Y. Kobayashi, S. Hishita, S. Ghosh and R. Klett 134 (1998) 61
Repair by radiation itself or not? A study of threonine irradiated by keV ion, W. Huang, Z. Yu and Y. Zhang 134 (1998) 202
Frequency dependence of ac conductance of neutron irradiated silicon detectors to fluences up to 10^{16} n/cm^2, N. Croitoru, G. David, P.G. Rancoita, M. Rattaggi and A. Seidman 134 (1998) 209
Measurements of the neutron yield and the neutron energy distribution from the ^{9}Be(d,n)^{10}B reaction on a thick Be target at an incident deuteron energy of 20.2 MeV, A. Belymam, A. Hoummada, J. Collot, P. de Saintignon, G. Mahout and B. Merkel 134 (1998) 217
Physical and chemical implications of 100 keV H^+ implantation of laser ablated PPS thin films, A. Das, S. Bera, S. Dhara and A. Patnaik 134 (1998) 377
Radiation effect on the luminescence of $LiYF_4:Er^{3+}$, S.P. Deshpande, S.J. Dhoble, W.K. Pokale, B.T. Deshmukh, R.B. Pode and T.K. Gundurao 134 (1998) 385
Effects of high intensity ultrasound in chemical etching of particle tracks in solid state nuclear track detectors, A.K. Pandey, P.C. Kalsi and R.H. Iyer 134 (1998) 393
Chemical tracks of heavy ions for 1,2,4,5-tetracyanobenzene anion radical formation, M. Taguchi, Y. Matsumoto, H. Namba, Y. Aoki and H. Hiratsuka (*Letter to the Editor*) 134 (1998) 427

Analysis of Materials

An improved method for the study of neutral species produced in processing plasmas, J.A. Rees, D.L. Seymour, C.L. Greenwood and A. Scott 134 (1998) 73
Heavy ion backscattering spectroscopy (HIBS) analysis of gallium arsenide diffusion into barium fluoride layers grown by molecular beam epitaxy, M.F. Stumborg, F. Santiago, T.K. Chu, K.A. Boulais and J.L. Price . . 134 (1998) 77
Rutherford backscattering of laterally heterogeneous structures: The determination of radial density distributions in ion tracks in collodium, D. Fink, M. Müller, P. Szimkoviak, R. Klett, J. Vacik, V. Hnatowicz and L.T. Chadderton 134 (1998) 87
Simulation of ERD spectra for a surface with a periodic roughness, A. Kitamura, T. Tamai, A. Taniike, Y. Furuyama, T. Maeda, N. Ogiwara and M. Saidoh 134 (1998) 98
RBS and ion channeling studies of Ag-doped $YBa_2Cu_3O_{7-\delta}$ targets and films, Y. Li, J.R. Liu, X.T. Cui and W.K. Chu 134 (1998) 107
Microstructural characterization of semi-interpenetrating polymer networks by positron lifetime spectroscopy, J.J. Singh, R.H. Pater and A. Eftekhari 134 (1998) 113
Matrix effects in SIMS analysis of high-dose boron implanted silicon wafers, H. Yamazaki 134 (1998) 121
PIXE analysis of trace pollutants in Chaliyar river water in Malabar, India, V.J. Kennedy, A. Augusthy, K.M. Varier, P. Magudapathy, S. Panchapakesan, C. Ramesh, K.G.M. Nair and V. Vijayan 134 (1998) 224
Characterisation of archaeological bronzes using PIXE, PIGE, RBS and AES spectrometries, A. Climent-Font, G. Demortier, C. Palacio, I. Montero, J.L. Ruvalcaba-Sil and D. Díaz 134 (1998) 229
Deuterium depth profiling in polymers using heavy ion elastic recoil detection, H. Ermer, O. Pfaff, W. Straub, M. Geoghegan and R. Brenn 134 (1998) 237
Rutherford backscattering spectroscopy of rough films: Experimental aspects, H. Metzner, Th. Hahn, M. Gossla, J. Conrad and J.-H. Bremer 134 (1998) 249
Transient magnetic fields and electron polarizations of H-like oxygen ions in crystalline iron and amorphous iron–boron compounds, R. Ernst, K.-H. Speidel, A. Gohla, L. Kleinen, H. Busch, U. Grabowy, V. Roth, B. Heller, G. Jakob and J. Gerber 134 (1998) 262
Characterization of single-crystalline Nb films on sapphire by RBS/channeling technique, S. Yamamoto, H. Naramoto, K. Narumi, B. Tsuchiya, Y. Aoki and H. Kudo 134 (1998) 400
Magnetic texture determination by means of the monochromatic circularly polarized Mössbauer spectroscopy, K. Szymański 134 (1998) 405

Ion Sources and Beam Optics

A simple retardation system for low-energy implantation of mass-separated radioactive ions, H. Muramatsu, H. Ishii, E. Tanaka, A. Osa, M. Koizumi, T. Sekine, T. Miura and M. Fujioka 134 (1998) 126
A new pulsed release method for element selective production of neutron rich isotopes near ^{208}Pb, P. Van Duppen, A. Andreyev, J. Äystö, A.-H. Evensen, M. Huhta, M. Huyse, A. Jokinen, M. Karny, E. Kugler, J. Kurpeta, J. Lettry, A. Nieminen, A. Plochocki, M. Ramdhane, H.L. Ravn, K. Rykaczewski, J. Szerypo, G. Walter, A. Wöhr and ISOLDE collaboration 134 (1998) 267
Analysis of van de Graaff ion source with Rutherford backscattering spectroscopy, C. Narayan, M. O'Connor, G.H.R. Kegel, A. Mittler and C. Brodeur 134 (1998) 271
Transmission ion microscopy using a quadrupole triplet as an objective lens, M.B.H. Breese and D.G. de Kerckhove (*Letter to the Editor*) 134 (1998) 431

Experimental Methods and Equipment

Measurement of the thermoluminescent response (supralinearity and efficiency) of LiF: Mg,Ti exposed to 0.7 MeV protons, I. Gamboa-deBuen, C. Ruiz, A. Oliver, K. López and M.E. Brandan 134 (1998) 136
Consideration of $R_2Fe_{14}B$ layers as targets with polarized electrons, J.M. Hoogduin and J. van Klinken (*Letter to the Editor*) 134 (1998) 149
A method for determining the 2π-counting efficiency of beta-particle sources, M.J. Berger 134 (1998) 276
Photoelectron spectroscopy experiments on singly charged positive-ions using synchrotron radiation, B. Rouvellou, J.-M. Bizau, J. Obert, S. Al Moussalami, N. Berland, C. Blancard, E. Bouisset, D. Cubaynes, S. Diehl, L. Journel, J.-C. Putaux, C. Vinsot and F.J. Wuilleumier 134 (1998) 287
$Lu_2S_3:Ce^{3+}$, A new red luminescing scintillator, J.C. van't Spijker, P. Dorenbos, C.P. Allier, C.W.E. van Eijk, A.R.H.F. Ettema and G. Huber (*Letter to the Editor*) 134 (1998) 304
A new three-angle energy-dispersive diffractometer, P. Barnes, A.C. Jupe, S.L. Colston, S.D. Jacques, A. Grant, T. Rathbone, M. Miller, S.M. Clark and R.J. Cernik (*Letter to the Editor*) 134 (1998) 310
A broad range YAP–plastic phoswich dosimeter, A.A. Fyodorov, W.P. Trower and R.F. Zuevsky 134 (1998) 413
Development of an in-air high-resolution PIXE system, K. Maeda, K. Hasegawa, H. Hamanaka and K. Ogiwara 134 (1998) 418

Letters to the Editor

Consideration of $R_2Fe_{14}B$ layers as targets with polarized electrons, J.M. Hoogduin and J. van Klinken 134 (1998) 149
$Lu_2S_3:Ce^{3+}$, A new red luminescing scintillator, J.C. van't Spijker, P. Dorenbos, C.P. Allier, C.W.E. van Eijk, A.R.H.F. Ettema and G. Huber 134 (1998) 304
A new three-angle energy-dispersive diffractometer, P. Barnes, A.C. Jupe, S.L. Colston, S.D. Jacques, A. Grant, T. Rathbone, M. Miller, S.M. Clark and R.J. Cernik 134 (1998) 310
Chemical tracks of heavy ions for 1,2,4,5-tetracyanobenzene anion radical formation, M. Taguchi, Y. Matsumoto, H. Namba, Y. Aoki and H. Hiratsuka 134 (1998) 427
Transmission ion microscopy using a quadrupole triplet as an objective lens, M.B.H. Breese and D.G. de Kerckhove 134 (1998) 431

Errata

Erratum to: "Statistical theory of charged-particle stopping and straggling in the presence of charge exchange" [Nucl. Instr. and Meth. B 69 (1992) 113], P. Sigmund 134 (1998) 435